# **IGBT for Automotive Application**

1200 V, 40 A

# AFGHL40T120RLD

#### Description

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop II Trench construction. Provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss, which is AEC Q101 qualified offer the optimum performance for both hard and soft switching topology in automotive application.

#### Features

- Extremely Efficient Trench with Field Stop Technology
- Maximum Junction Temperature:  $T_J = 175^{\circ}C$
- Short Circuit Withstand Time 9 µs
- Low Saturation Voltage:  $V_{CE(Sat)} = 1.75 V (Typ.) @ I_C = 40 A$
- 100% of the Parts Tested for I<sub>LM</sub> (Note 2)
- Fast Switching
- Tighten Parameter Distribution
- AEC-Q101 Qualified and PPAP Capable
- This Device is Pb–Free, Halogen Free/BFR Free and is RoHS Compliant

#### **Typical Applications**

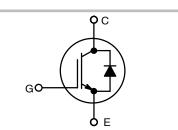
- Automotive HEV-EV E-Compressor
- Automotive HEV-EV PTC Heater
- Automotive HEV–EV Onboard Chargers
- Automotive HEV-EV DC-DC Converters



## **ON Semiconductor®**

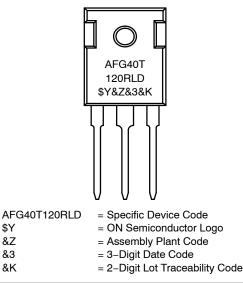
#### www.onsemi.com

V <sub>CES</sub>	Ι <sub>C</sub>	V <sub>CE(Sat)</sub>
1200 V	40 A	1.75 V (Typ.)









#### **ORDERING INFORMATION**

Device	Package	Shipping
AFGHL40T120RLD	TO-247-3L	30 Units / Rail

#### **MAXIMUM RATINGS**

Description	Symbol	Value	Units
Collector to Emitter Voltage	V <sub>CES</sub>	1200	V
Gate to Emitter Voltage	V <sub>GES</sub>	±20	V
Transient Gate to Emitter Voltage	7	±30	
Collector Current @ $T_C = 25^{\circ}C$ (Note 1)	Ι <sub>C</sub>	48	А
Collector Current @ T <sub>C</sub> = 100°C		40	
Pulsed Collector Current (Note 2)	I <sub>LM</sub>	160	А
Pulsed Collector Current (Note 3)	I <sub>CM</sub>	160	А
Diode Forward Current @ $T_C = 25^{\circ}C$ (Note 1)	١ <sub>F</sub>	48	А
Diode Forward Current @ T <sub>C</sub> = 100°C		40	
Pulsed Diode Maximum Forward Current	I <sub>FM</sub>	160	А
Maximum Power Dissipation @ $T_C = 25^{\circ}C$	PD	529	W
Maximum Power Dissipation @ T <sub>C</sub> = 100°C		264	-
Short Circuit Withstand Time $V_{GE}$ = 15 V, $V_{CE}$ = 600 V, $T_{J}$ = 150°C	SCWT	9	μs
Operating Junction Temperature / Storage Temperature Range	T <sub>J,</sub> T <sub>STG</sub>	–55 to +175	°C
Maximum Lead Temp. For Soldering Purposes, 1/8" from case for 5 seconds	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Value limited by bond wire. 2.  $V_{CC} = 600 \text{ V}$ ,  $V_{GE} = 15 \text{ V}$ ,  $I_C = 160 \text{ A}$ ,  $R_G = 15 \Omega$ , Inductive Load, 100% Tested 3. Repetitive rating: pulse width limited by max. Junction temperature.

#### **THERMAL CHARACTERISTICS**

Rating	Symbol	Max.	Units
Thermal Resistance, Junction to Case, for IGBT	$R_{ ext{ heta}JC}$	0.28	°C/W
Thermal Resistance, Junction to Case, Max for Diode	$R_{ ext{ heta}JC}$	0.47	°C/W
Thermal Resistance, Junction to Ambient, Max	$R_{ extsf{ heta}JA}$	40	°C/W

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Unit
OFF CHARACTERISTICS						
Collector-emitter Breakdown Voltage, Gate-emitter Short-circuited	$V_{GE}$ = 0 V, I <sub>C</sub> = 1mA	BVCES	1250	-	-	V
Temperature Coefficient of Breakdown Voltage	$V_{GE}$ = 0 V, I <sub>C</sub> = 1mA	$\Delta BV_{CES}/\Delta T_{J}$	-	1.4	-	V/°C
Collector-emitter Cut-off Current, Gate-emitter Short-circuited	$V_{GE}$ = 0 V, $V_{CE}$ = $V_{CES}$	ICES	-	-	40	μΑ
Gate Leakage Current, Collector-emitter Short-circuited	$V_{GE} = V_{GES}, V_{CE} = 0 V$	IGES	-	-	±400	nA
ON CHARACTERISTICS	·					

Gate-emitter Threshold Voltage	$V_{GE} = V_{CE}, I_C = 40 \text{ mA}$	VGE(th)	5.3	6.3	7.3	V
Collector-emitter Saturation Voltage	$V_{GE}$ = 15 V, I <sub>C</sub> = 40 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 40 A, T <sub>J</sub> = 175°C	VCE(sat)	-	1.75 2.09	2.1 -	V

#### **ELECTRICAL CHARACTERISTICS** ( $T_J$ = 25°C unless otherwise specified) (continued)

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Unit
DYNAMIC CHARACTERISTICS						
Input Capacitance	$V_{CE}$ = 30 V, $V_{GE}$ = 0 V, f = 1 MHz	Cies	-	8755	-	pF
Output Capacitance		C <sub>oes</sub>	-	302	-	
Reverse Transfer Capacitance		C <sub>res</sub>	-	162	-	
SWITCHING CHARACTERISTICS, IN	IDUCTIVE LOAD					
Turn-on Delay Time	$T_J = 25^{\circ}C$	t <sub>d(on)</sub>	-	43	_	ns
Rise Time	$V_{CC} = 600 \text{ V}, \text{ I}_{C} = 20 \text{ A}$ Rg = 5 $\Omega$	tr	-	18	-	
Turn-off Delay Time	V <sub>GE</sub> = 15 V Inductive Load	t <sub>d(off)</sub>	-	222	-	
Fall Time		t <sub>f</sub>	-	53	-	
Turn-on Switching Loss		E <sub>on</sub>	-	1.6	-	mJ
Turn-off Switching Loss	7	E <sub>off</sub>	-	0.45	-	
Total Switching Loss	7	E <sub>ts</sub>	-	2.05	-	
Turn-on Delay Time	$T_J = 25^{\circ}C$	t <sub>d(on)</sub>	-	48	-	ns
Rise Time	$V_{CC} = 600 \text{ V}, \text{ I}_{C} = 40 \text{ A}$ $\text{Rg} = 5 \Omega$ $V_{GE} = 15 \text{ V}$ Inductive Load	t <sub>r</sub>	-	32	_	
Turn-off Delay Time		t <sub>d(off)</sub>	-	208	_	
Fall Time		t <sub>f</sub>	-	68	-	1
Turn-on Switching Loss	_	E <sub>on</sub>	-	3.4	-	mJ
Turn-off Switching Loss		E <sub>off</sub>	-	1.2	-	1
Total Switching Loss	-	E <sub>ts</sub>	-	4.6	-	
Turn-on Delay Time	$T_J = 175$ °C V <sub>CC</sub> = 600 V, I <sub>C</sub> = 20 A Rg = 5 Ω	t <sub>d(on)</sub>	-	40	-	ns
Rise Time		t <sub>r</sub>	-	20	-	
Turn-off Delay Time	V <sub>GE</sub> = 15 V Inductive Load	t <sub>d(off)</sub>	-	252	-	
Fall Time		t <sub>f</sub>	-	156	-	
Turn-on Switching Loss	-	Eon	-	2.5	-	mJ
Turn-off Switching Loss	-	E <sub>off</sub>	-	1.08	-	
Total Switching Loss	-	E <sub>ts</sub>	-	3.58	-	
Turn-on Delay Time	T <sub>J</sub> = 175°C	t <sub>d(on)</sub>	-	44	-	ns
Rise Time	$V_{CC} = 600 \text{ V}, \text{ I}_{C} = 40 \text{ A}$ Rg = 5 $\Omega$	t <sub>r</sub>	-	32	-	
Turn-off Delay Time	V <sub>GE</sub> = 15 V Inductive Load	t <sub>d(off)</sub>	-	236	_	
Fall Time		t <sub>f</sub>	-	164	_	
Turn-on Switching Loss	-	Eon	-	4.9	-	mJ
Turn-off Switching Loss	-	E <sub>off</sub>	-	2.5	_	
Total Switching Loss	-	E <sub>ts</sub>	-	7.4	_	
Total Gate Charge	$V_{CE}$ = 600 V, I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V	Qg	-	395	_	nC
Gate to Emitter Charge	-	Q <sub>ge</sub>	-	72	_	
Gate to collector Charge		Q <sub>gc</sub>	-	198	_	
DIODE CHARACTERISTICS	-					
Forward Voltage	I <sub>F</sub> = 40 A, T <sub>J</sub> = 25°C I <sub>F</sub> = 40 A, T <sub>J</sub> = 175°C	V <sub>F</sub>		1.51 1.54	2.0	V
Reverse Recovery Energy	$T_J = 25^{\circ}C$	E <sub>rec</sub>	-	0.74	-	mJ
Diode Reverse Recovery Time	V <sub>R</sub> = 600 V, I <sub>F</sub> = 20 A dI <sub>F</sub> /dt = 1000 A/μs	T <sub>rr</sub>	-	143	-	ns
Diode Reverse Recovery Charge		Q <sub>rr</sub>	-	2546	-	nC

### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified) (continued)

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Unit
DIODE CHARACTERISTICS						
Reverse Recovery Energy	$T_{J} = 25^{\circ}C$	E <sub>rec</sub>	-	1.14	-	mJ
Diode Reverse Recovery Time	V <sub>R</sub> = 600 V, I <sub>F</sub> = 40 A dI <sub>F</sub> /dt = 1000 A/μs	T <sub>rr</sub>	-	195	-	ns
Diode Reverse Recovery Charge		Q <sub>rr</sub>	-	3761	-	nC
Reverse Recovery Energy	$ \begin{array}{l} T_J = 175^{\circ}C \\ V_R = 600 \text{ V}, \text{ I}_F = 20 \text{ A} \\ \text{dI}_F/\text{dt} = 1000 \text{ A}/\mu\text{s} \end{array} $	E <sub>rec</sub>	-	1.92	-	mJ
Diode Reverse Recovery Time		T <sub>rr</sub>	-	212	-	ns
Diode Reverse Recovery Charge		Q <sub>rr</sub>	-	5242	-	nC
Reverse Recovery Energy	$T_{J} = 175^{\circ}C$	E <sub>rec</sub>	-	2.768	-	mJ
Diode Reverse Recovery Time	V <sub>R</sub> = 600 V, I <sub>F</sub> = 40 A dI <sub>F</sub> /dt = 1000 A/μs	T <sub>rr</sub>	-	286	-	ns
Diode Reverse Recovery Charge		Q <sub>rr</sub>	-	7321	-	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### **TYPICAL CHARACTERISTICS**

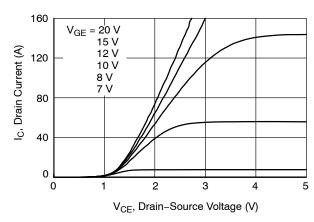


Figure 1. Typical Output Characteristics (25°C)

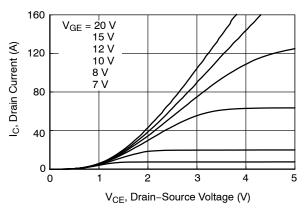


Figure 2. Typical Output Characteristics (175°C)

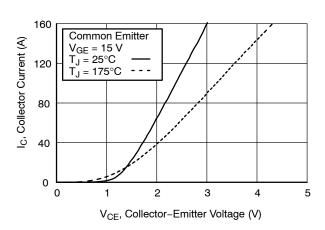


Figure 3. Typical Saturation Voltage Characteristics

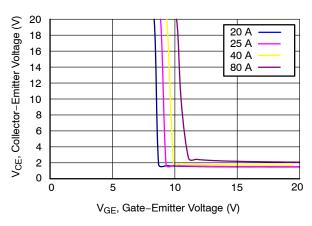


Figure 5. Saturation Voltage vs. V<sub>GE</sub> (25°C)

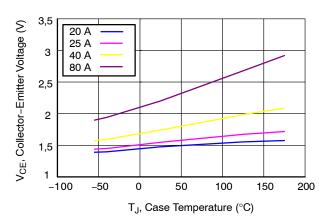


Figure 4. Saturation Voltage vs. Case Temperature at Variant Current Level

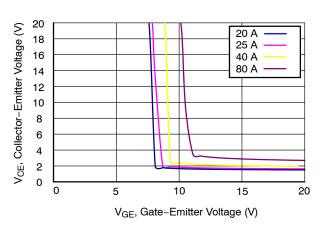


Figure 6. Saturation Voltage vs. V<sub>GE</sub> (175°C)

#### TYPICAL CHARACTERISTICS (continued)

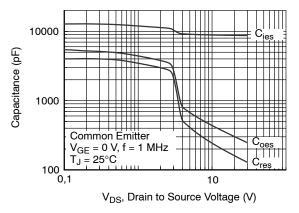


Figure 7. Capacitance Characteristics

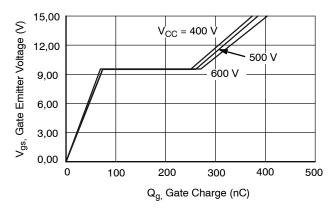


Figure 8. Gate Charge Characteristics

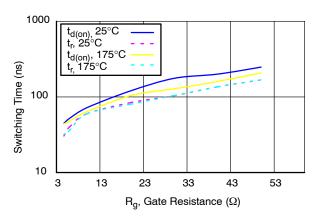


Figure 9. Turn-on Characteristics vs. Gate Resistance

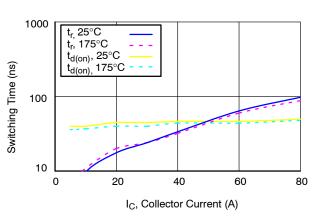


Figure 11. Turn-on Characteristics vs. Collector Current

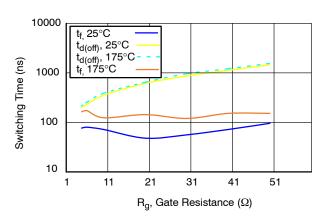


Figure 10. Turn-off Characteristics vs. Gate Resistance

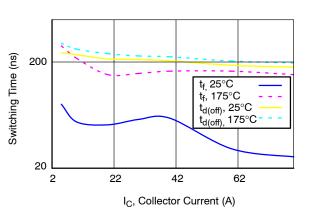


Figure 12. Turn-off Characteristics vs. Collector Current

#### TYPICAL CHARACTERISTICS (continued)

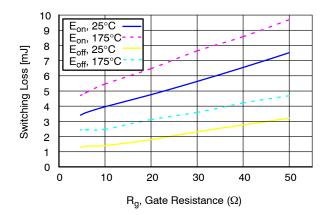


Figure 13. Switching Loss vs. Gate Resistance

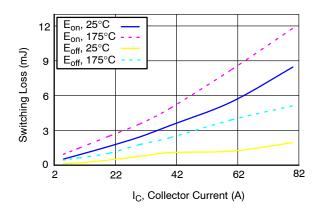


Figure 14. Switching Loss vs. Collector Current

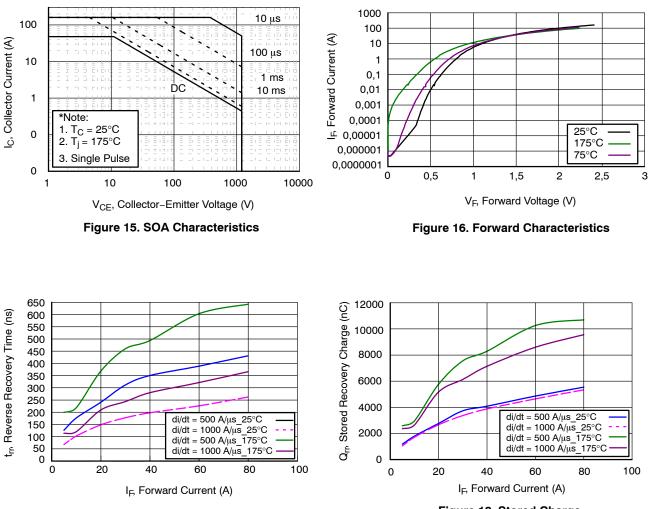


Figure 17. Reverse Recovery Time

Figure 18. Stored Charge

#### TYPICAL CHARACTERISTICS (continued)

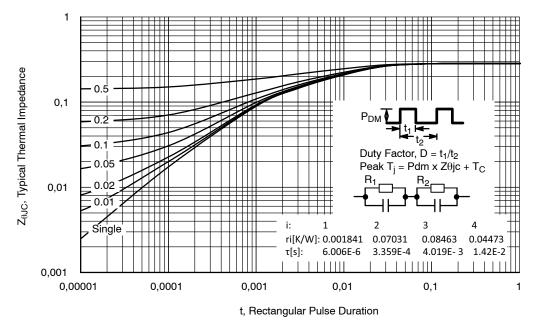


Figure 19. Transient Thermal Impedance of IGBT

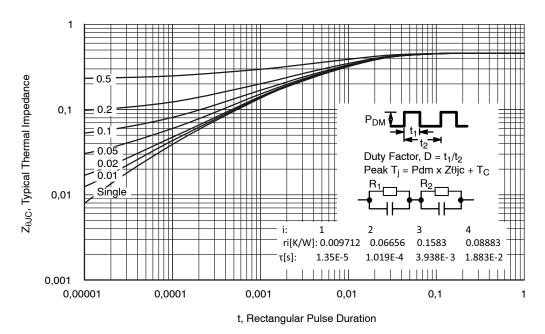


Figure 20. Transient Thermal Impedance of Diode

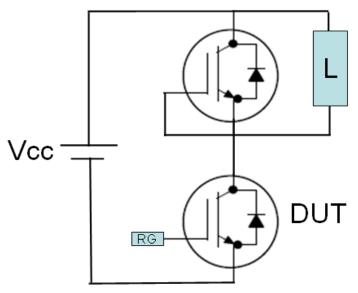
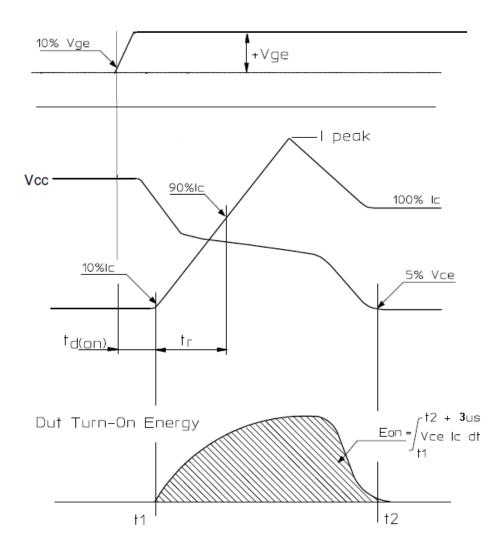
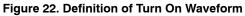


Figure 21. Test Circuit for Switching Characteristics





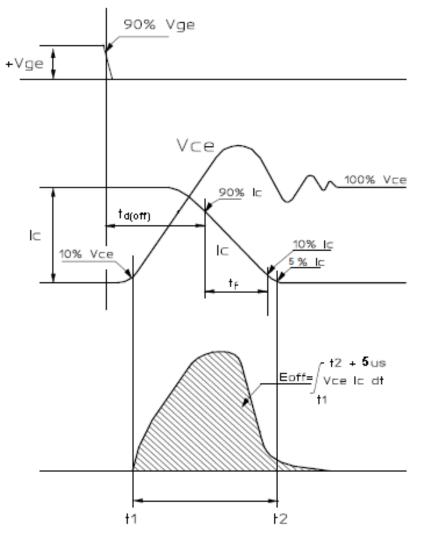
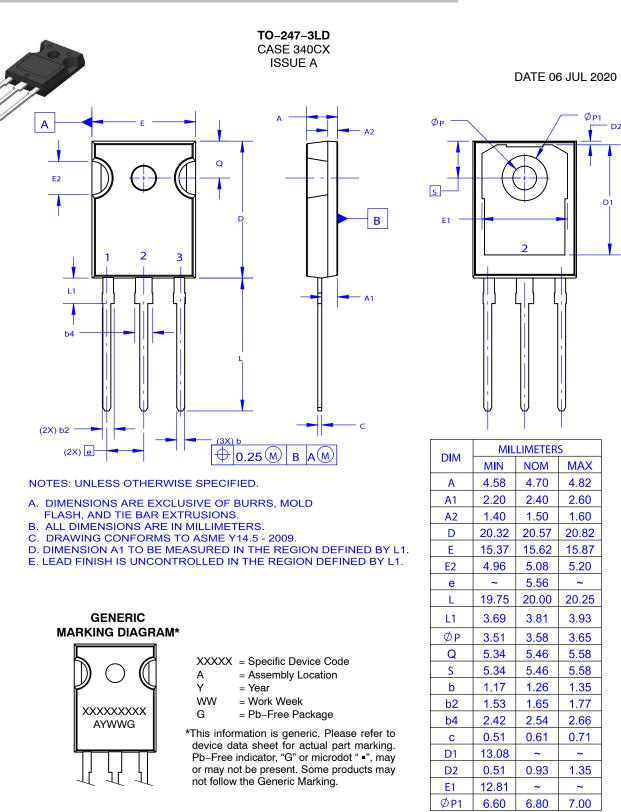


Figure 23. Definition of Turn Off Waveform



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